

10/051375  
10/17/05  
10051375  
10/17/05

PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10051375	01-17-2002	372	--	2821	--

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\*\*CONTINUING DATA VERIFIED:

\*\* FOREIGN APPLICATIONS VERIFIED:

REPUBLIC OF KOREA 2001 48463 08/11/2001

REPUBLIC OF KOREA 2001-52030 08/28/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	ATTORNEY DOCKET NO
Foreign priority claimed	<input type="checkbox"/> yes <input type="checkbox"/> no	35 URC 113 conditions met	<input type="checkbox"/> yes <input type="checkbox"/> no
Varied and Acknowledged Examiner's initials			
NTLF : Nonlinearity error correcting method and phase angle measuring method for displacement measurement in two-frequency laser interferometer and displacement measurement system using same			

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg.	Print Fig.
TERMINAL DISCLAIMER		Primary Examiner		Application Examiner
		PREPARED FOR ISSUE		
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